

8-Mbit (512K x 16) Static RAM

Features

- Very high speed: 45 ns
- Wide voltage range: 2.2V–3.6V and 4.5V–5.5V
- Ultra low standby power
 - Typical Standby current: 2 μ A
 - Maximum Standby current: 8 μ A
- Ultra low active power
 - Typical active current: 1.8 mA at f = 1 MHz
- Easy memory expansion with $\overline{\text{CE}}$ and $\overline{\text{OE}}$ features
- Automatic power down when deselected
- CMOS for optimum speed and power
- Available in Pb-free 44-pin TSOP II package

Functional Description

The CY62157ESL is a high performance CMOS static RAM organized as 512K words by 16 bits. This device features advanced circuit design to provide ultra low active current. This is ideal for providing More Battery Life[™] (MoBL[®]) in portable applications such as cellular telephones. The device also has an automatic power down feature that significantly reduces power consumption when addresses are not toggling. Place the device

into standby mode when deselected ($\overline{\text{CE}}$ HIGH or both $\overline{\text{BHE}}$ and $\overline{\text{BLE}}$ are HIGH). The input or output pins (IO₀ through IO₁₅) are placed in a high impedance state when:

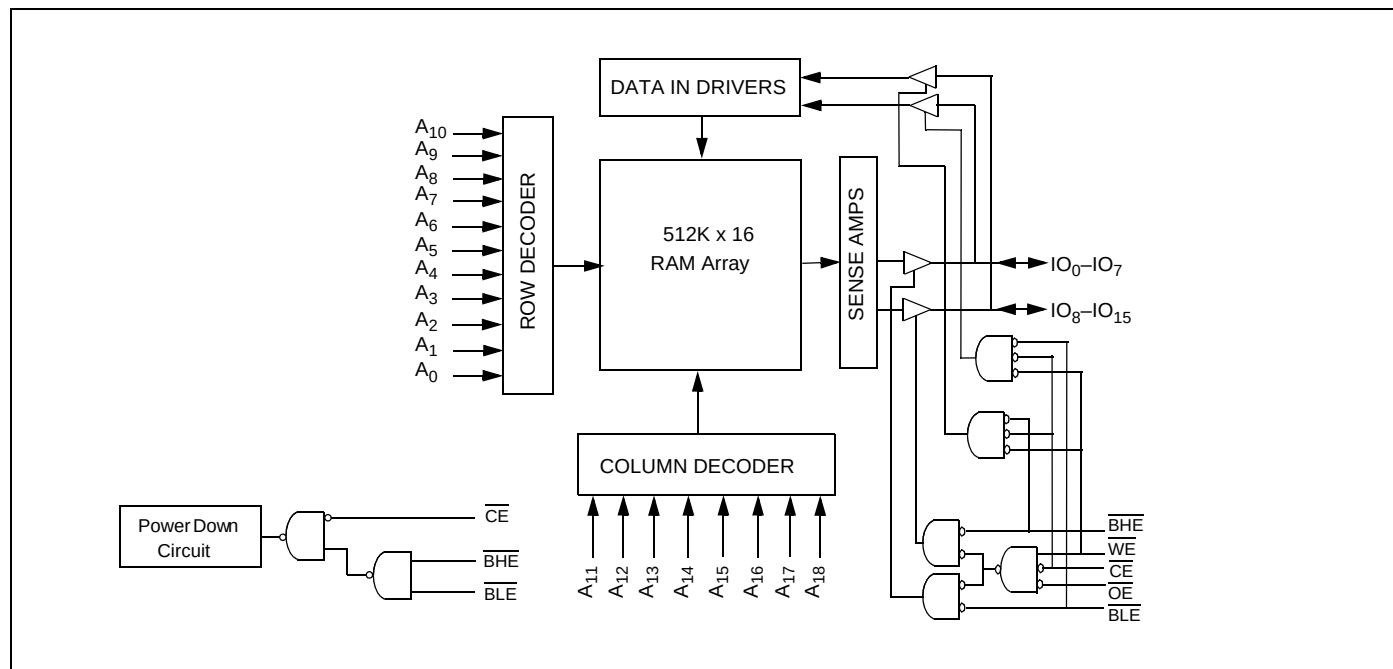
- Deselected ($\overline{\text{CE}}$ HIGH)
- Outputs are disabled ($\overline{\text{OE}}$ HIGH)
- Both Byte High Enable and Byte Low Enable are disabled ($\overline{\text{BHE}}$, $\overline{\text{BLE}}$ HIGH)
- Write operation is active ($\overline{\text{CE}}$ LOW and $\overline{\text{WE}}$ LOW)

To write to the device, take Chip Enable ($\overline{\text{CE}}$) and Write Enable ($\overline{\text{WE}}$) inputs LOW. If Byte Low Enable ($\overline{\text{BLE}}$) is LOW, then data from IO pins (IO₀ through IO₇) is written into the location specified on the address pins (A₀ through A₁₈). If Byte High Enable ($\overline{\text{BHE}}$) is LOW, then data from IO pins (IO₈ through IO₁₅) is written into the location specified on the address pins (A₀ through A₁₈).

To read from the device, take Chip Enable ($\overline{\text{CE}}$) and Output Enable ($\overline{\text{OE}}$) LOW while forcing the Write Enable ($\overline{\text{WE}}$) HIGH. If Byte Low Enable ($\overline{\text{BLE}}$) is LOW, then data from the memory location specified by the address pins appear on IO₀ to IO₇. If Byte High Enable ($\overline{\text{BHE}}$) is LOW, then data from memory appears on IO₈ to IO₁₅. See the [Truth Table on page 10](#) for a complete description of read and write modes.

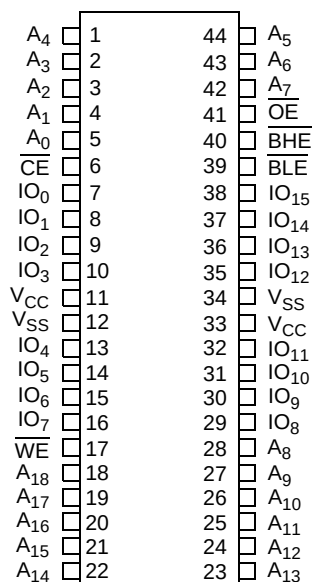
For best practice recommendations, refer to the Cypress application note [AN1064, SRAM System Guidelines](#).

Logic Block Diagram



Pin Configuration

Figure 1. 44-Pin TSOP II (Top View)



Product Portfolio

Product	Range	V _{CC} Range (V) ^[1]	Speed (ns)	Power Dissipation					
				Operating I _{CC} , (mA)				Standby, I _{SB2} (μA)	
				f = 1MHz		f = f _{max}			
				Typ ^[2]	Max	Typ ^[2]	Max	Typ ^[2]	Max
CY62157ESL	Industrial	2.2V–3.6V and 4.5V–5.5V	45	1.8	3	18	25	2	8

Notes

1. Datasheet specifications are not guaranteed for V_{CC} in the range of 3.6V to 4.5V.
2. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 3V, and V_{CC} = 5V, T_A = 25°C.

Maximum Ratings

Exceeding the maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature –65°C to +150°C

Ambient Temperature with
Power Applied –55°C to +125°C

Supply Voltage to Ground Potential.....–0.5V to 6.0V

DC Voltage Applied to Outputs
in High-Z State^[3, 4]–0.5V to 6.0V

DC Input Voltage^[3, 4]–0.5V to 6.0V

Output Current into Outputs (LOW)..... 20 mA

Static Discharge Voltage..... >2001V
(MIL-STD-883, Method 3015)

Latch up Current..... >200 mA

Operating Range

Device	Range	Ambient Temperature	V _{CC} ^[5]
CY62157ESL	Industrial	–40°C to +85°C	2.2V–3.6V, and 4.5V–5.5V

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions	45 ns			Unit
			Min	Typ ^[2]	Max	
V _{OH}	Output HIGH Voltage	2.2 ≤ V _{CC} ≤ 2.7	I _{OH} = –0.1 mA		2.0	V
		2.7 ≤ V _{CC} ≤ 3.6	I _{OH} = –1.0 mA		2.4	
		4.5 ≤ V _{CC} ≤ 5.5	I _{OH} = –1.0 mA		2.4	
V _{OL}	Output LOW Voltage	2.2 ≤ V _{CC} ≤ 2.7	I _{OL} = 0.1 mA		0.4	V
		2.7 ≤ V _{CC} ≤ 3.6	I _{OL} = 2.1mA		0.4	
		4.5 ≤ V _{CC} ≤ 5.5	I _{OL} = 2.1mA		0.4	
V _{IH}	Input HIGH Voltage	2.2 ≤ V _{CC} ≤ 2.7	1.8		V _{CC} + 0.3	V
		2.7 ≤ V _{CC} ≤ 3.6	2.2		V _{CC} + 0.3	
		4.5 ≤ V _{CC} ≤ 5.5	2.2		V _{CC} + 0.5	
V _{IL}	Input LOW Voltage	2.2 ≤ V _{CC} ≤ 2.7	–0.3		0.6	V
		2.7 ≤ V _{CC} ≤ 3.6	–0.3		0.8	
		4.5 ≤ V _{CC} ≤ 5.5	–0.5		0.8	
I _{IX}	Input Leakage Current	GND ≤ V _I ≤ V _{CC}	–1		+1	μA
I _{OZ}	Output Leakage Current	GND ≤ V _O ≤ V _{CC} , Output Disabled	–1		+1	μA
I _{CC}	V _{CC} Operating Supply Current	f = f _{max} = 1/t _{RC}	V _{CC} = V _{CCmax}		18	mA
		f = 1 MHz	I _{OUT} = 0 mA, CMOS levels		1.8	
I _{SB1}	Automatic CE Power down Current — CMOS Inputs	CE ≥ V _{CC} – 0.2V, V _{IN} ≥ V _{CC} – 0.2V or V _{IN} ≤ 0.2V, f = f _{max} (Address and Data Only), f = 0 (OE, BHE, BLE and WE), V _{CC} = V _{CC(max)}		2	8	μA
I _{SB2}	Automatic CE Power down Current — CMOS Inputs	CE ≥ V _{CC} – 0.2V, V _{IN} ≥ V _{CC} – 0.2V or V _{IN} ≤ 0.2V, f = 0, V _{CC} = V _{CC(max)}		2	8	μA

Notes

3. V_{IL}(min) = –2.0V for pulse durations less than 20 ns.

4. V_{IH}(max) = V_{CC} + 0.75V for pulse durations less than 20 ns.

5. Full Device AC operation assumes a 100 μs ramp time from 0 to V_{CC} (min) and 200 μs wait time after V_{CC} stabilization.

Capacitance

Tested initially and after any design or process changes that may affect these parameters.

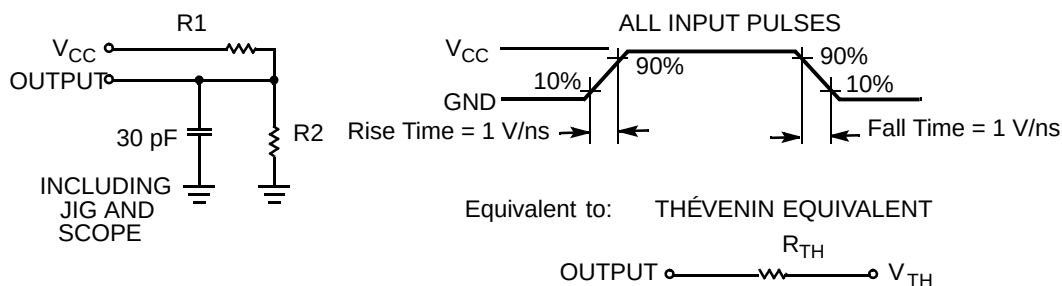
Parameter	Description	Test Conditions	Max	Unit
C_{IN}	Input Capacitance	$T_A = 25^\circ\text{C}$, $f = 1\text{ MHz}$, $V_{CC} = V_{CC(\text{typ})}$	10	pF
C_{OUT}	Output Capacitance		10	pF

Thermal Resistance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	TSOP II	Unit
Θ_{JA}	Thermal Resistance (Junction to Ambient)	Still Air, soldered on a 3 × 4.5 inch, two-layer printed circuit board	77	$^\circ\text{C/W}$
Θ_{JC}	Thermal Resistance (Junction to Case)		13	$^\circ\text{C/W}$

AC Test Loads and Waveforms



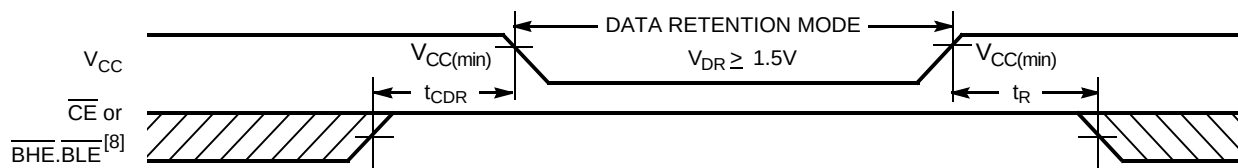
Parameters	2.5V	3.0V	5.0V	Unit
$R1$	16667	1103	1800	Ω
$R2$	15385	1554	990	Ω
R_{TH}	8000	645	639	Ω
V_{TH}	1.20	1.75	1.77	V

Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions	Min	Typ ^[2]	Max	Unit
V_{DR}	V_{CC} for Data Retention		1.5			V
I_{CCDR}	Data Retention Current	$\overline{CE} \geq V_{CC} - 0.2V$, $V_{IN} \geq V_{CC} - 0.2V$ or $V_{IN} \leq 0.2V$	$V_{CC} = 1.5V$	2	5	μA
			$V_{CC} = 2.0V$	2	8	
$t_{CDR}^{[6]}$	Chip Deselect to Data Retention Time		0			ns
$t_R^{[7]}$	Operation Recovery Time		t_{RC}			ns

Data Retention Waveform



Notes

6. Tested initially and after any design or process changes that may affect these parameters.
7. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \geq 100 \mu s$ or stable at $V_{CC(min)} \geq 100 \mu s$.
8. $\overline{BHE.BLE}$ is the AND of both $\overline{BHE}$ and $\overline{BLE}$. Deselect the chip by either disabling chip enable signals or by disabling both $\overline{BHE}$ and $\overline{BLE}$.

Switching Characteristics

Over the Operating Range ^[9]

Parameter	Description	45 ns		Unit
		Min	Max	
Read Cycle				
t _{RC}	Read Cycle Time	45		ns
t _{AA}	Address to Data Valid		45	ns
t _{OHA}	Data Hold from Address Change	10		ns
t _{ACE}	$\overline{CE}$ LOW to Data Valid		45	ns
t _{DOE}	$\overline{OE}$ LOW to Data Valid		22	ns
t _{LZOE}	$\overline{OE}$ LOW to LOW-Z ^[10]	5		ns
t _{HZOE}	$\overline{OE}$ HIGH to High-Z ^[10, 11]		18	ns
t _{LZCE}	$\overline{CE}$ LOW to Low-Z ^[10]	10		ns
t _{HZCE}	$\overline{CE}$ HIGH to High-Z ^[10, 11]		18	ns
t _{PU}	$\overline{CE}$ LOW to Power Up	0		ns
t _{PD}	$\overline{CE}$ HIGH to Power Down		45	ns
t _{DBE}	$\overline{BLE/BHE}$ LOW to Data Valid		45	ns
t _{LZBE}	$\overline{BLE/BHE}$ LOW to Low-Z ^[10, 12]	5		ns
t _{HZBE}	$\overline{BLE/BHE}$ HIGH to HIGH-Z ^[10, 11]		18	ns
Write Cycle ^[13]				
t _{WC}	Write Cycle Time	45		ns
t _{SCE}	$\overline{CE}$ LOW to Write End	35		ns
t _{AW}	Address Setup to Write End	35		ns
t _{HA}	Address Hold from Write End	0		ns
t _{SA}	Address Setup to Write Start	0		ns
t _{PWE}	$\overline{WE}$ Pulse Width	35		ns
t _{BW}	$\overline{BLE/BHE}$ LOW to Write End	35		ns
t _{SD}	Data Setup to Write End	25		ns
t _{HD}	Data Hold from Write End	0		ns
t _{HZWE}	$\overline{WE}$ LOW to High-Z ^[10, 11]		18	ns
t _{LZWE}	$\overline{WE}$ HIGH to Low-Z ^[10]	10		ns

Notes

9. Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3V, and output loading of the specified I_{OL}/I_{OH} as shown in the [AC Test Loads and Waveforms on page 4](#).
10. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZBE} is less than t_{LZBE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any device.
11. t_{HZOE} , t_{HZCE} , t_{HZBE} , and t_{HZWE} transitions are measured when the outputs enter a high-impedance state.
12. If both byte enables are toggled together, this value is 10 ns.
13. The internal write time of the memory is defined by the overlap of $\overline{WE}$, $\overline{CE} = V_{IL}$, $\overline{BHE}$, $\overline{BLE}$ or both = V_{IL} . All signals must be active to initiate a write and any of these signals can terminate a write by going inactive. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.

Switching Waveforms

Figure 2. Read Cycle No.1: Address Transition Controlled. [14, 15]

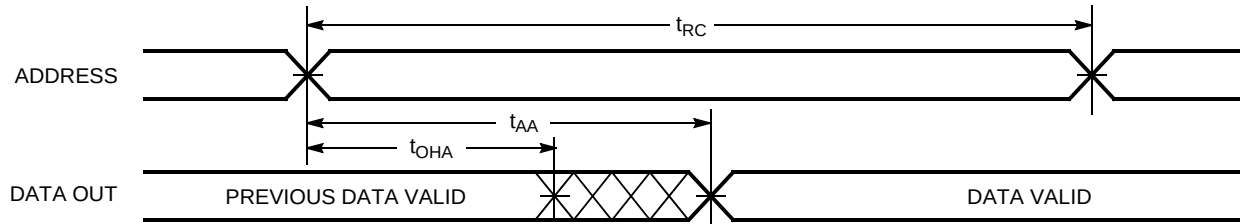
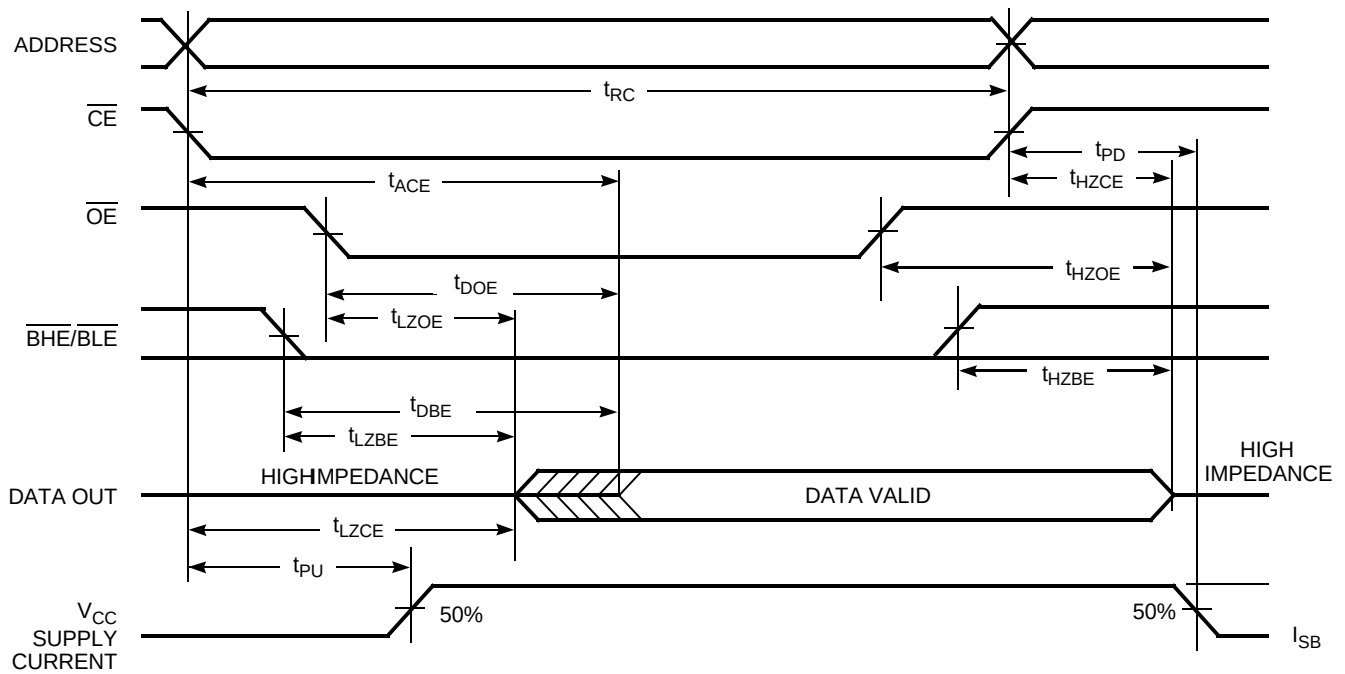


Figure 3. Read Cycle No. 2: $\overline{\text{OE}}$ Controlled [15, 16]



Notes

14. The device is continuously selected. $\overline{\text{OE}}$, $\overline{\text{CE}}$ = V_{IL} , $\overline{\text{BHE}}$, $\overline{\text{BLE}}$, or both = V_{IL} .
15. $\overline{\text{WE}}$ is HIGH for read cycle.
16. Address valid before or similar to $\overline{\text{CE}}$, $\overline{\text{BHE}}$, $\overline{\text{BLE}}$ transition LOW.

Switching Waveforms (continued)

Figure 4. Write Cycle No 1: $\overline{\text{WE}}$ Controlled [13, 17, 18]

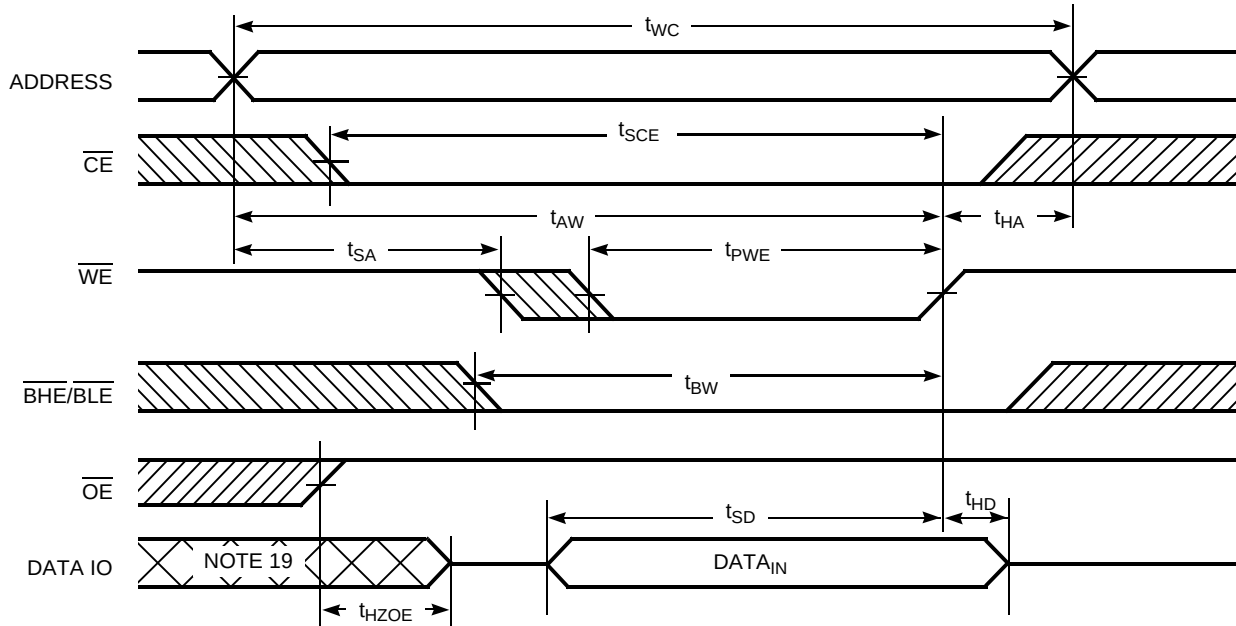
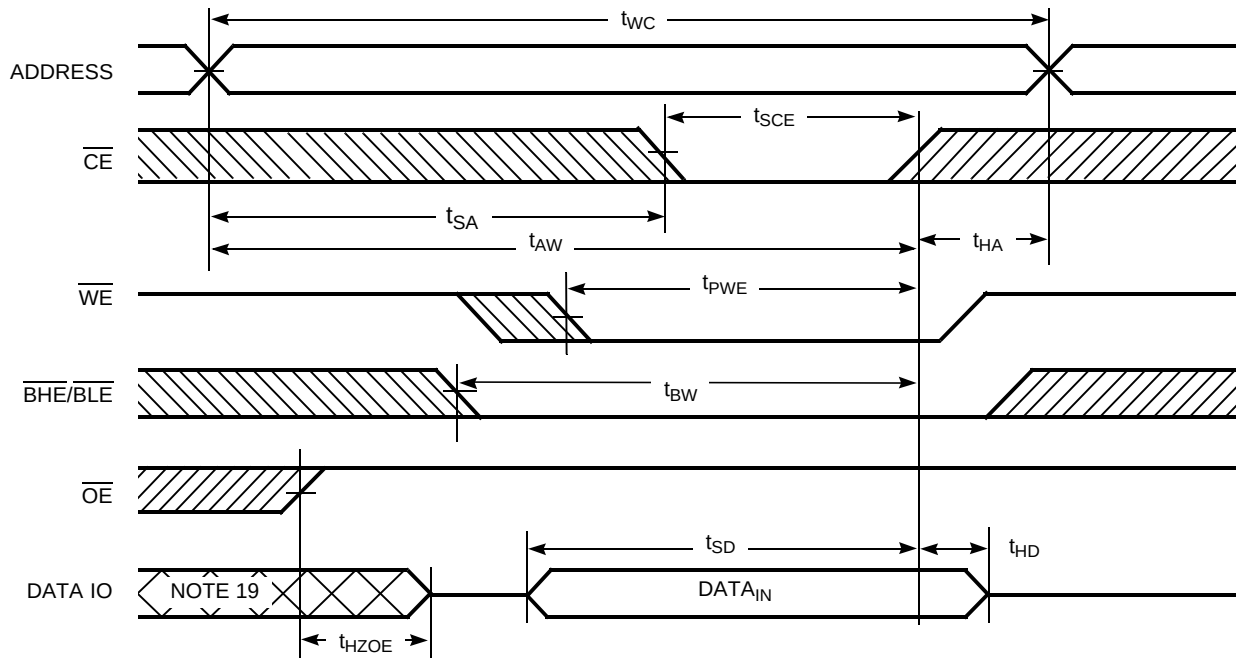


Figure 5. Write Cycle 2: $\overline{\text{CE}}$ Controlled [13, 17, 18]



Notes

17. Data IO is high impedance if $\overline{\text{OE}} = V_{IH}$.
18. If $\overline{\text{CE}}$ goes HIGH simultaneously with $\text{WE} = V_{IH}$, the output remains in a high impedance state.
19. During this period, the IOs are in output state. Do not apply input signals.

Switching Waveforms (continued)

Figure 6. Write Cycle 3: $\overline{\text{WE}}$ controlled, $\overline{\text{OE}}$ LOW [18]

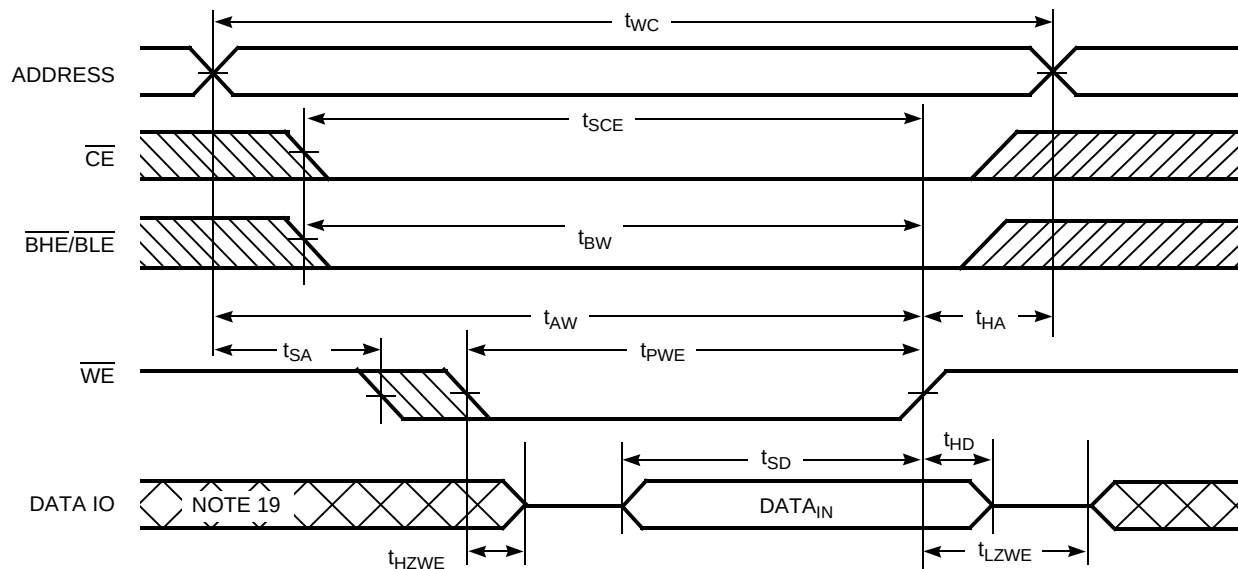
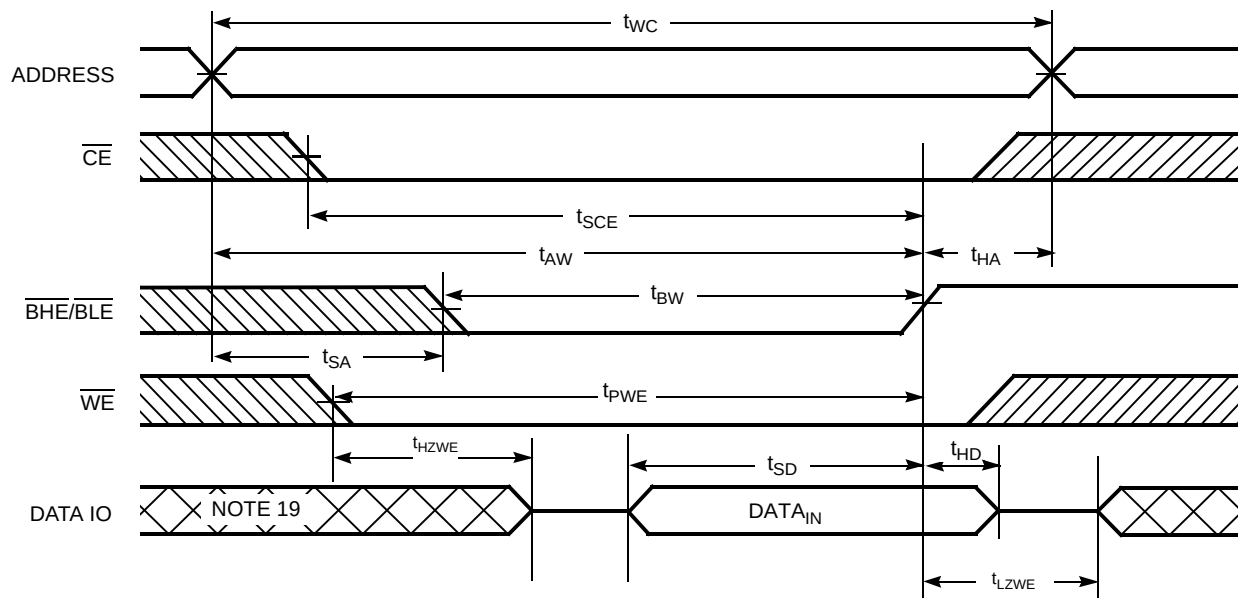


Figure 7. Write Cycle 4: $\overline{\text{BHE/BLE}}$ Controlled, $\overline{\text{OE}}$ LOW [18]



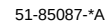
Truth Table

$\overline{CE}$	$\overline{WE}$	$\overline{OE}$	$\overline{BHE}$	$\overline{BLE}$	Inputs/Outputs	Mode	Power
H	X	X	X	X	High-Z	Deselect/Power down	Standby (I_{SB})
X	X	X	H	H	High-Z	Deselect/Power down	Standby (I_{SB})
L	H	L	L	L	Data Out (IO_0 – IO_{15})	Read	Active (I_{CC})
L	H	L	H	L	Data Out (IO_0 – IO_7); IO_8 – IO_{15} in High-Z	Read	Active (I_{CC})
L	H	L	L	H	Data Out (IO_8 – IO_{15}); IO_0 – IO_7 in High-Z	Read	Active (I_{CC})
L	H	H	L	L	High-Z	Output Disabled	Active (I_{CC})
L	H	H	H	L	High-Z	Output Disabled	Active (I_{CC})
L	H	H	L	H	High-Z	Output Disabled	Active (I_{CC})
L	L	X	L	L	Data In (IO_0 – IO_{15})	Write	Active (I_{CC})
L	L	X	H	L	Data In (IO_0 – IO_7); IO_8 – IO_{15} in High-Z	Write	Active (I_{CC})
L	L	X	L	H	Data In (IO_8 – IO_{15}); IO_0 – IO_7 in High-Z	Write	Active (I_{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY62157ESL-45ZSXI	51-85087	44-pin Thin Small Outline Package Type II (Pb-free)	Industrial

Figure 8. 44-Pin TSOP II, 51-85087



Document History Page

Document Title: CY62157ESL MoBL® 8-Mbit (512K x 16) Static RAM Document Number: 001-43141				
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	1875228	See ECN	VKN/AESA	New Data Sheet

© Cypress Semiconductor Corporation, 2008. The information contained herein is subject to change without notice. Cypress Semiconductor Corporation assumes no responsibility for the use of any circuitry other than circuitry embodied in a Cypress product. Nor does it convey or imply any license under patent or other rights. Cypress products are not warranted nor intended to be used for medical, life support, life saving, critical control or safety applications, unless pursuant to an express written agreement with Cypress. Furthermore, Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress products in life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Any Source Code (software and/or firmware) is owned by Cypress Semiconductor Corporation (Cypress) and is protected by and subject to worldwide patent protection (United States and foreign), United States copyright laws and international treaty provisions. Cypress hereby grants to licensee a personal, non-exclusive, non-transferable license to copy, use, modify, create derivative works of, and compile the Cypress Source Code and derivative works for the sole purpose of creating custom software and or firmware in support of licensee product to be used only in conjunction with a Cypress integrated circuit as specified in the applicable agreement. Any reproduction, modification, translation, compilation, or representation of this Source Code except as specified above is prohibited without the express written permission of Cypress.

Disclaimer: CYPRESS MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARD TO THIS MATERIAL, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Cypress reserves the right to make changes without further notice to the materials described herein. Cypress does not assume any liability arising out of the application or use of any product or circuit described herein. Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress' product in a life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Use may be limited by and subject to the applicable Cypress software license agreement.